Welcome to the fifteenth Asian Test Symposium (ATS’06). Since 1992, ATS has been held every year in various Asian cities as the largest symposia that focus on testing of integrated circuits and systems. This year ATS is being held in Fukuoka, Japan.

We have received 127 technical paper submissions from all over the world, including 33 from North America, 20 from Europe, 20 from Mainland China, 18 from Japan, 17 from Taiwan, 7 from India, 10 from other Asian countries and regions, and 1 from Uruguay. Each paper was sent to at least three reviewers for evaluation. The program committee meeting was held on July 7, 2006, at Kyoto Sangyo University, and 63 papers were selected based on the reviewers’ rating and comments. The selected papers, which cover nearly all aspects of the key area of VLSI testing, were allocated into 21 technical sessions. We have also received 7 submissions to industry poster session.

In addition to the technical sessions, the ATS program includes three plenary sessions, and two half-day tutorials. Two keynote addresses in the plenary sessions are given by Dr. Rochit Rajsuman and Prof. Irith Pomeranz. One panel session is organized by Dr. Fidel Muradali. Two half-day tutorials are offered in cooperation with the Test Technology Test Education Program (TTEP) of IEEE Test Technology Technical Council (TTTC). One is on delay testing by Dr. Srinivas Patil and the other is on memory test and self-test by Dr. R.Dean Adams.

Finally we would like to thank the reviewers, the program committee, the organizing committee, and the ATS Steering Committee. And we also thank to all the authors who submitted their work to ATS 2006, and the program participants for their contribution at the symposium.

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